

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:	)	Confirmation No.: 5721
Hidekazu MIYAIRI et al.	)	Examiner: Jeffrey R. West
Serial No. 10/808,499	)	Group Art Unit: 2857
Filed: March 25, 2004	)	
For: METHOD FOR TESTING	)	
SEMICONDUCTOR FILM,	)	
SEMICONDUCTOR DEVICE AND	)	
MANUFACTURING METHOD	)	
THEREOF	)	

**AMENDMENT**

Honorable Commissioner of Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the Official Action dated July 22, 2010, please consider the following amendments and remarks in connection with the above-identified application.

**Amendments to the Claims** are reflected in the listing of claims, which begins on page 2 of this paper.

**Remarks** begin on page 12 of this paper.